L Number	Hits	Search Text	DB	Time stamp
1	2	("6246248").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/13 15:57
2	544	measur$6 near10 (pulse adj width) near5 current	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/13 15:16
3	23	determin$4 near5 fault near5 locat$4 with (semiconductor or IC or chip)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/13 15:12
4	1	(measur$6 near10 (pulse adj width) near5 current) and (determin$4 near5 fault near5 locat$4 with (semiconductor or IC or chip))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/13 15:11
5	25	(determin$4 or presum$4) near5 fault near5 locat$4 with (semiconductor or IC or chip)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/13 15:59
6	4439	"25" and (pulse adj width) near5 current	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/13 15:16
7	2	((determin$4 or presum$4) near5 fault near5 locat$4 with (semiconductor or IC or chip)) and (pulse adj width) near5 current	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/13 15:16
8	8811	324/765,763,158.1,73.1.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/13 15:58
9	4	((determin$4 or presum$4) near5 fault near5 locat$4 with (semiconductor or IC or chip)) and 324/765,763,158.1,73.1.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/13 15:58
10	95	(determin$4 or presum$4 or test$4) with fault near5 locat$4 with (semiconductor or IC or chip)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/13 16:00
11	4	((determin$4 or presum$4 or test$4) with fault near5 locat$4 with (semiconductor or IC or chip)) and (measur$6 near10 (pulse adj width) near5 current)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/13 16:02
12	599	714/733.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/13 16:02
13	2	714/733.ccls. and ((determin$4 or presum$4 or test$4) with fault near5 locat$4 with (semiconductor or IC or chip))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/13 16:03
14	335	702/64.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/13 16:03

15	0	702/64.ccls. and ((determin$4 or presum$4 or test$4) with fault near5 locat$4 with (semiconductor or IC or chip))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/13 16:03
16	81	700/306.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/13 16:04
17	0	700/306.ccls. and ((determin$4 or presum$4 or test$4) with fault near5 locat$4 with (semiconductor or IC or chip))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/13 16:04
18	1592	327/141,334.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/13 16:04
19	0	327/141,334.ccls. and ((determin$4 or presum$4 or test$4) with fault near5 locat$4 with (semiconductor or IC or chip))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/13 16:04
-	28822	test$4 near3 pattern	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/15 14:48
-	9647	transient near3 current	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/15 14:49
-	2799	fault near3 analysis	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/15 14:50
-	1	(test$4 near3 pattern) with (transient near3 current) with (fault near3 analysis)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/15 14:50
-	1	(test$4 near3 pattern) and (transient near3 current) and (fault near3 analysis)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/15 14:50
-	12	(test$4 near3 pattern) with (transient near3 current)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/15 14:55
-	36	(test$4 near3 pattern) with (fault near3 analysis)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/15 14:55
-	27	((test$4 near3 pattern) with (fault near3 analysis)) and integrated	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/15 14:55
-	8	("3159787" | "3302109" | "3636443" | "3982240" | "4110698" | "4637006" | "4720671" | "4908802").PN.	USPAT	2003/04/15 15:07
-	22	5436559.URPN.	USPAT	2003/04/15 15:08

| - | 4 | (("6246248") or ("5949798")).PN. | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/04/28 12:46 |
| - | 2 | ("6246248").PN. | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/11/05 14:45 |